

Notice of References Cited

Application/Control No.		nt Under	
09/992,569	Reexamination KIMURA, HAJIME		
Examiner	Art Unit		
Leland R. Jorgensen	2675	Page 1 of 1	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,229,506 B1	05-2001	Dawson et al.	345/82
	В	US-5,576,857 A	11-1996	Takemura, Yasuhiko	349/42
	С	US-6,628,363 B1	09-2003	Sano et al.	349/151
	D	US-5,888,858 A	03-1999	Yamazaki et al.	438/162
	Е	US-6,535,185 B2	03-2003	Kim et al.	345/76
	F	US-6,091,203 A	07-2000	Kawashima et al.	315/169.3
	G	US-6,570,338 B2	05-2003	Bae, Sung Joon	315/169.3
	Н	US-5,818,068 A	10-1998	Sasaki et al.	257/59
	1	US-6,011,532 A	01-2000	Yanai et al.	345/92
	J	US-			
	K	US-			
	٦	US-	,		
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q				,	
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Sedra and Smith, Microelectronic Circuits, 3rd ed. (New York; Saunders College Publishing, 1991) pp. 462 – 466
	v	
	w	
	х	•

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.